

# 4-Mbit (512 K × 8) Static RAM

#### **Features**

■ Very high speed: 45 ns

■ Voltage range: 4.5 V to 5.5 V

■ Pin compatible with CY62148B

■ Ultra low standby power

□ Typical standby current: 1 µA

□ Maximum standby current: 7 µA (Industrial)

■ Ultra low active power

□ Typical active current: 2.0 mA at f = 1 MHz

■ Easy memory expansion with  $\overline{CE}$ , and  $\overline{OE}$  features

■ Automatic power-down when deselected

Complementary metal oxide semiconductor (CMOS) for optimum speed and power

 Available in Pb-free 32-pin thin small outline package (TSOP) II and 32-pin small-outline integrated circuit (SOIC)<sup>[1]</sup> packages

## **Functional Description**

The CY62148E is a high performance CMOS static RAM organized as 512 K words by 8-bits. This device features

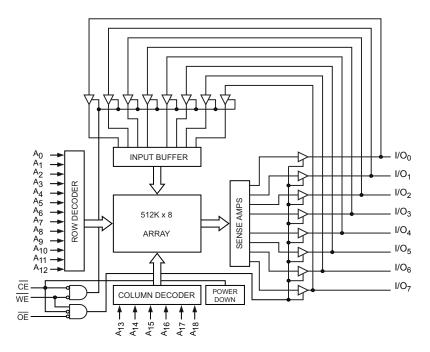
advanced circuit design to provide ultra low standby current. This is ideal for providing More Battery  $\mathsf{Life}^{\,\,\mathrm{TM}}$  (MoBL®) in portable applications. The device also has an automatic power-down feature that significantly reduces power consumption when addresses are not toggling. Placing the device into standby mode reduces power consumption by more than 99% when deselected (CE HIGH). The eight input and output pins (I/O0 through I/O7) are placed in a high impedance state when the device is deselected (CE HIGH), Outputs are disabled (OE HIGH), or during an active Write operation (CE LOW and WE LOW).

 $\underline{\text{To w}}$  rite to the device, take Chip Enable  $(\overline{\text{CE}})$  and Write Enable  $(\overline{\text{WE}})$  inputs LOW. Data on the eight I/O pins (I/O<sub>0</sub> through I/O<sub>7</sub>) is then written into the location specified on the address pins (A<sub>0</sub> through A<sub>18</sub>).

To read from the device, take Chip Enable  $(\overline{CE})$  and Output Enable  $(\overline{OE})$  LOW while forcing Write Enable  $(\overline{WE})$  HIGH. Under these conditions, the contents of the memory location specified by the address pins appear on the I/O pins.

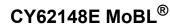
The CY62148E device is suitable for interfacing with processors that have TTL I/P levels. It is not suitable for processors that require CMOS I/P levels. Please see Electrical Characteristics on page 4 for more details and suggested alternatives.

## **Logic Block Diagram**



#### Note

1. SOIC package is available only in 55 ns speed bin.





## Contents

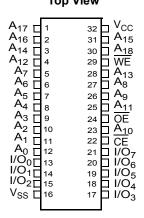
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## **Pin Configurations**

Figure 1. 32-pin SOIC/TSOP II pinout Top View



#### **Product Portfolio**

									Power D	issipatio	on			
Produc	.4		V <sub>CC</sub> Range (V) Speed Operating I <sub>CC</sub> (mA)		Operating I <sub>CC</sub> (mA)		Standby	I (11 <b>A</b> )						
Floud	, L					(ns)	f = 1 MHz		(ns) $f = 1 \text{ MHz}$ $f = f_{\text{max}}$		f = f <sub>max</sub>		Standby I <sub>SB2</sub> (µA)	
		Range	Min	<b>Typ</b> [2]	Max		<b>Typ</b> [2]	Max	<b>Typ</b> [2]	Max	<b>Typ</b> [2]	Max		
CY62148ELL	TSOP II	Industrial	4.5	5.0	5.5	45	2	2.5	15	20	1	7		
CY62148ELL	SOIC	Industrial / Automotive-A	4.5	5.0	5.5	55	2	2.5	15	20	1	7		

#### Note

<sup>2.</sup> Typical values are included for reference only and are not guaranteed or tested. Typical values are measured at V<sub>CC</sub> = V<sub>CC(typ)</sub>, T<sub>A</sub> = 25 °C.



## **Maximum Ratings**

Exceeding maximum ratings may shorten the useful life of the device. User guidelines are not tested. Storage temperature ......-65 °C to + 150 °C Ambient temperature with Supply voltage to ground potential ......-0.5 V to 6.0 V (V<sub>CCmax</sub> + 0.5 V) DC voltage applied to outputs in high Z state  $^{[3,\,4]}$  .....-0.5 V to 6.0 V (V $_{\rm CCmax}$  + 0.5 V)

DC input voltage $^{[3, 4]}$ 0.5 V to 6.0 V (V <sub>CCmax</sub> + 0.5	V)
Output current into outputs (LOW)20 r	nΑ
Static discharge voltage (per MIL-STD-883, Method 3015)> 2001	I V
Latch-up current> 200 r	nΑ

### **Operating Range**

Device	Range	Ambient Temperature	<b>V</b> <sub>CC</sub> <sup>[5]</sup>	
CY62148E	Industrial / Automotive-A	–40 °C to +85 °C	4.5 V to 5.5 V	

#### **Electrical Characteristics**

Over the operating range

Parameter	Description	Test Con	ditions		45 n	s		Unit		
Parameter	Description	lest Con	uitions	Min	<b>Typ</b> [7]	Max	Min	Typ [7]	Max	Oilit
V <sub>OH</sub> <sup>[8]</sup>	Output HIGH voltage	V <sub>CC</sub> = 4.5 V, I <sub>OH</sub> = -	-1 mA	2.4	_	-	2.4	_	-	V
		$V_{CC} = 5.5 \text{ V}, I_{OH} = -$	-0.1 mA	_	_	3.4 <sup>[8]</sup>	-	-	3.4 <sup>[8]</sup>	V
V <sub>OL</sub>	Output LOW voltage	I <sub>OL</sub> = 2.1 mA		_	_	0.4	_	_	0.4	V
V <sub>IH</sub>	Input HIGH voltage	$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$	/	2.2	_	V <sub>CC</sub> + 0.5	2.2	_	V <sub>CC</sub> + 0.5	V
V <sub>IL</sub>	Input LOW voltage	$V_{CC}$ = 4.5 V to 5.5 V	For TSOPII package	-0.5	-	0.8	_	_	-	V
			For SOIC package	-	_	-	-0.5	_	0.6 <sup>[9]</sup>	
I <sub>IX</sub>	Input leakage current	$GND \le V_1 \le V_{CC}$		-1	_	+1	-1	_	+1	μΑ
I <sub>OZ</sub>	Output leakage current	GND $\leq$ $V_O \leq$ $V_{CC}$ , ou	tput disabled	-1	_	+1	-1	_	+1	μA
I <sub>CC</sub>	V <sub>CC</sub> operating supply	$f = f_{max} = 1/t_{RC}$	$V_{CC} = V_{CC(max)}$	_	15	20	_	15	20	mA
	current	f = 1 MHz	I <sub>OUT</sub> = 0 mA CMOS levels	_	2	2.5	_	2	2.5	
I <sub>SB2</sub> <sup>[10]</sup>	Automatic CE power-down current – CMOS inputs	$\overline{\text{CE}} \ge \text{V}_{\text{CC}} - 0.2 \text{ V}, \\ \text{V}_{\text{IN}} \ge \text{V}_{\text{CC}} - 0.2 \text{ V} \text{ c} \\ \text{f} = 0, \text{V}_{\text{CC}} = \text{V}_{\text{CC(max)}}$	or V <sub>IN</sub> ≤ 0.2 V, x)	-	1	7	-	1	7	μA

#### Notes

- 3.  $V_{IL(min)}$  = -2.0 V for pulse durations less than 20 ns for I  $\leq$  30 mA. 4.  $V_{IH(max)}$  =  $V_{CC}$  + 0.75 V for pulse durations less than 20 ns.
- Full device AC operation assumes a minimum of 100 μs ramp time from 0 to V<sub>CC(min)</sub> and 200 μs wait time after V<sub>CC</sub> stabilization.
- 6. SOIC package is available only in 55 ns speed bin.
- Typical values are included for reference and are not guaranteed or tested. Typical values are measured at V<sub>CC</sub> = V<sub>CC(typ)</sub>, T<sub>A</sub> = 25 °C.
   Please note that the maximum V<sub>OH</sub> limit for this device does not exceed minimum CMOS V<sub>IH</sub> of 3.5V. If you are interfacing this SRAM with 5 V legacy processors that require a minimum V<sub>IH</sub> of 3.5 V, please refer to Application Note AN6081 for technical details and options you may consider.
- Under DC conditions the device meets a V<sub>IL</sub> of 0.8 V. However, in dynamic conditions Input LOW Voltage applied to the device must not be higher than 0.6 V. This is applicable to SOIC package only.
- 10. Chip enable ( $\overline{\text{CE}}$ ) must be HIGH at CMOS level to meet the I<sub>SB2</sub> / I<sub>CCDR</sub> spec. Other inputs can be left floating.



## Capacitance

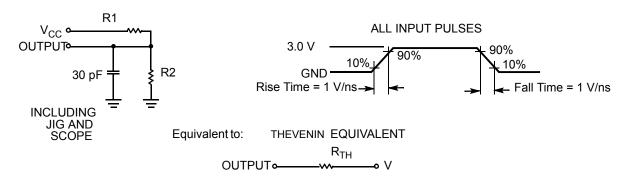
Parameter [11]	Description	Test Conditions	Max	Unit
C <sub>IN</sub>	Input capacitance	$T_A = 25$ °C, $f = 1$ MHz, $V_{CC} = V_{CC(Typ)}$	10	pF
C <sub>OUT</sub>	Output capacitance		10	pF

### **Thermal Resistance**

Parameter [11]	Description	Test Conditions	32-pin SOIC Package	32-pin TSOP II Package	Unit
$\Theta_{JA}$		Still air, soldered on a 3 × 4.5 inch, two-layer printed circuit board	75	77	°C/W
$\Theta_{\sf JC}$	Thermal resistance (junction to case)		10	13	°C/W

## **AC Test Loads and Waveforms**

Figure 2. AC Test Loads and Waveforms



Parameter [11]	5.0 V	Unit
R1	1800	Ω
R2	990	Ω
R <sub>TH</sub>	639	Ω
V <sub>TH</sub>	1.77	V

#### Note

<sup>11.</sup> Tested initially and after any design or process changes that may affect these parameters.



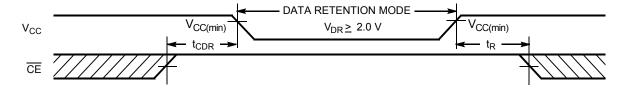
#### **Data Retention Characteristics**

Over the operating range

Parameter	Description	Condition	Min	Typ <sup>[12]</sup>	Max	Unit	
$V_{DR}$	V <sub>CC</sub> for data retention			2	_	_	V
ICCDR <sup>[13]</sup>	Data retention current	$\begin{split} &V_{CC} = V_{DR}, \\ &\overline{CE} \geq V_{CC} - 0.2 \text{ V}, \\ &V_{IN} \geq V_{CC} - 0.2 \text{ V or} \\ &V_{IN} \leq 0.2 \text{ V} \end{split}$	Industrial / Automotive-A	-	1	7	μА
t <sub>CDR</sub>	Chip deselect to data retention time			0	_	_	ns
t <sub>R</sub> <sup>[14]</sup>	Operation recovery time		TSOP II	45	_	_	ns
			SOIC	55	_	-	ns

### **Data Retention Waveform**

Figure 3. Data Retention Waveform



<sup>12.</sup> Typical values are included for reference and are not guaranteed or tested. Typical values are measured at  $V_{CC} = V_{CC(typ)}$ ,  $T_A = 25$  °C. 13. Chip enable ( $\overline{CE}$ ) must be HIGH at CMOS level to meet the  $I_{SB2} / I_{CCDR}$  spec. Other inputs can be left floating. 14. Full device operation requires linear  $V_{CC}$  ramp from  $V_{DR}$  to  $V_{CC(min)} > 100 \ \mu s$  or stable at  $V_{CC(min)} > 100 \ \mu s$ .



## **Switching Characteristics**

Over the operating range

[15 16]		45	ns	55 r		
Parameter [15, 16]	Description	Min	Max	Min	Max	Unit
Read Cycle			•	•	•	
t <sub>RC</sub>	Read cycle time	45	_	55	_	ns
t <sub>AA</sub>	Address to data valid	_	45	_	55	ns
t <sub>OHA</sub>	Data hold from address change	10	_	10	_	ns
t <sub>ACE</sub>	CE LOW to data valid	_	45	-	55	ns
t <sub>DOE</sub>	OE LOW to data valid	_	22	-	25	ns
t <sub>LZOE</sub>	OE LOW to low Z [18]	5	_	5	_	ns
t <sub>HZOE</sub>	OE HIGH to high Z [18, 19]	_	18	_	20	ns
t <sub>LZCE</sub>	CE LOW to low Z [18]	10	_	10	_	ns
t <sub>HZCE</sub>	CE HIGH to high Z [18, 19]	_	18	_	20	ns
t <sub>PU</sub>	CE LOW to power-up	0	_	0	_	ns
t <sub>PD</sub>	CE HIGH to power-down	_	45	_	55	ns
Write Cycle [20]		•				
t <sub>WC</sub>	Write cycle time	45	_	55	_	ns
t <sub>SCE</sub>	CE LOW to write end	35	_	40	_	ns
t <sub>AW</sub>	Address setup to write end	35	_	40	_	ns
t <sub>HA</sub>	Address hold from write end	0	_	0	_	ns
t <sub>SA</sub>	Address setup to write start	0	_	0	_	ns
t <sub>PWE</sub>	WE pulse width	35	_	40	_	ns
t <sub>SD</sub>	Data setup to write end	25	_	25	_	ns
t <sub>HD</sub>	Data hold from write end		_	0	_	ns
t <sub>HZWE</sub>	WE LOW to high Z [18, 19]	-	18	-	20	ns
t <sub>LZWE</sub>	WE HIGH to low Z [18]	10	_	10	_	ns

#### Notes

<sup>15.</sup> In an earlier revision of this device, under a specific application condition, READ and WRITE operations were limited to switching of the chip enable signal as described in the Application Note AN66311. However, the issue has been fixed and in production now, and hence, this Application Notes is no longer applicable. It is available for download on our website as it contains information on the date code of the parts, beyond which the fix has been in production.

<sup>16.</sup> Test conditions for all parameters other than tri-state parameters assume signal transition time of 3 ns or less, timing reference levels of 1.5 V, input pulse levels of 0 to 3 V, and output loading of the specified loL/loH as shown in the Figure 2 on page 5.
17. SOIC package is available only in 55 ns speed bin.
18. At any temperature and voltage condition, the specified loL/LoE is less than tLZOE, the specified that the couple specified that the cou



## **Switching Waveforms**

Figure 4. Read Cycle No. 1 (Address Transition Controlled) [21, 22]

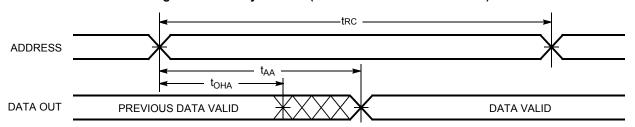


Figure 5. Read Cycle No. 2 (OE Controlled) [22, 23]

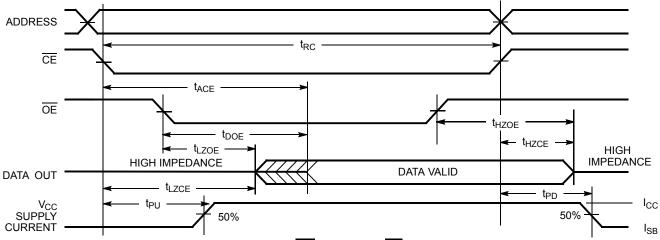
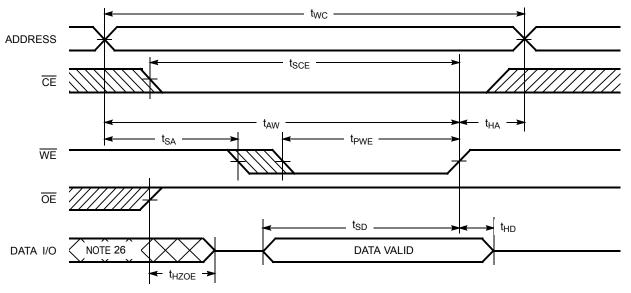


Figure 6. Write Cycle No. 1 (WE Controlled, OE HIGH During Write) [24, 25]



- 21. <u>Dev</u>ice is continuously selected. <del>OE</del>, <del>CE</del> = V<sub>IL</sub>.

  22. WE is HIGH for read cycles.

  23. Address valid before or similar to <del>CE</del> transition LOW.

  24. <u>Data</u> I/O is high impedance if <del>OE</del> = V<sub>IL</sub>.

  25. If <del>CE</del> goes HIGH simultaneously with WE HIGH, the output remains in high impedance state.

  26. During this period, the I/Os are in output state and input signals must not be applied.



## Switching Waveforms (continued)

Figure 7. Write Cycle No. 2 (CE Controlled) [27, 28]

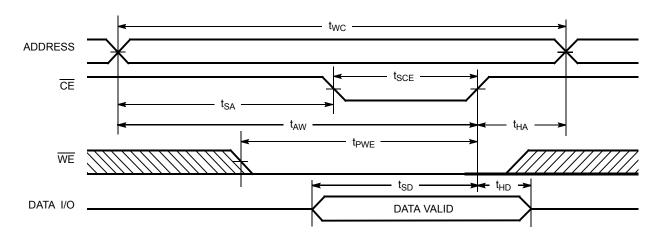
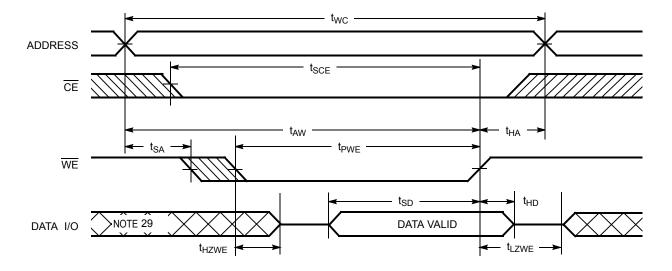


Figure 8. Write Cycle No. 3 ( $\overline{\text{WE}}$  Controlled,  $\overline{\text{OE}}$  LOW) [28]



<sup>27.</sup> Data I/O is high impedance if  $\overline{\text{OE}} = \text{V}_{\text{IH}}$ .

28. If  $\overline{\text{CE}}$  goes HIGH simultaneously with WE HIGH, the output remains in high impedance state.

29. During this period, the I/Os are in output state and input signals must not be applied.



## **Truth Table**

CE	WE	ŌĒ	I/O Mode		Power
H [30]	X	Х	High Z	Deselect/power-down	Standby (I <sub>SB</sub> )
L	Н	L	Data out	Read	Active (I <sub>CC</sub> )
L	L	Х	Data in	Write	Active (I <sub>CC</sub> )
L	Н	Н	High Z	Selected, outputs disabled	Active (I <sub>CC</sub> )

Note 30. Chip enable  $(\overline{CE})$  must be HIGH at CMOS level to meet the  $I_{SB2}$  /  $I_{CCDR}$  spec. Other inputs can be left floating.



### **Ordering Information**

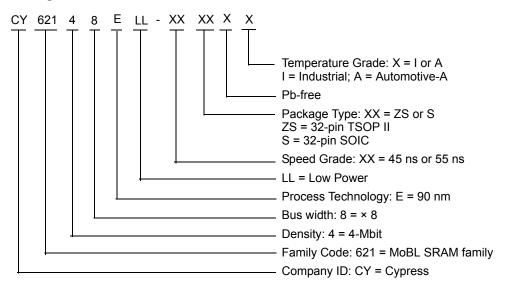
Table 1 lists the CY62148E MoBL<sup>®</sup> key package features and ordering codes. The table contains only the parts that are currently available. If you do not see what you are looking for, contact your local sales representative. For more information, visit the Cypress website at www.cypress.com and refer to the product summary page at http://www.cypress.com/products.

Table 1. Key features and Ordering Information

Speed (ns)	Ordering Code	Package Diagram	Package Type	Operating Range
45	CY62148ELL-45ZSXI	51-85095	32-pin TSOP II (Pb-free)	Industrial
	CY62148ELL-45ZSXA	51-85095	32-pin TSOP II (Pb-free)	Automotive-A
55	CY62148ELL-55SXI	51-85081	32-pin SOIC (Pb-free)	Industrial
	CY62148ELL-55SXA	51-85081	32-pin SOIC (Pb-free)	Automotive-A

Contact your local Cypress sales representative for availability of these parts.

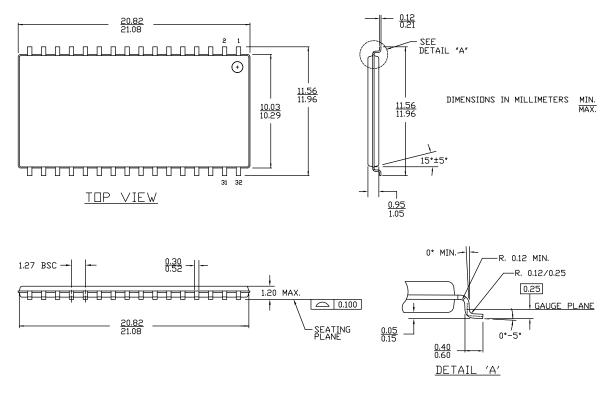
#### **Ordering Code Definitions**





## **Package Diagrams**

Figure 9. 32-pin TSOP II (20.95 × 11.76 × 1.0 mm) ZS32 Package Outline, 51-85095

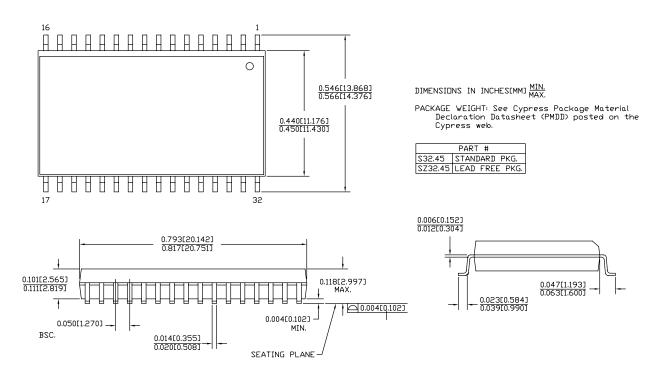


51-85095 \*B



# Package Diagrams (continued)

Figure 10. 32-pin SOIC (450 Mil) S32.45/SZ32.45 Package Outline, 51-85081



51-85081 \*E



# **Acronyms**

Acronym Description	
CE	Chip Enable
CMOS Complementary Metal Oxide Semiconductor	
I/O Input/Output	
OE	Output Enable
MoBL More Battery Life	
SOIC	Small Outline Integrated Circuit
SRAM	Static Random Access Memory
TSOP Thin Small Outline Package	
WE Write Enable	

## **Document Conventions**

### **Units of Measure**

Symbol	Unit of Measure		
°C	degree Celsius		
MHz	megahertz		
μΑ	microampere		
μs	microsecond		
mA	milliampere		
ns	nanosecond		
Ω	ohm		
%	percent		
pF	picofarad		
V	volt		
W	watt		



# **Document History Page**

Document Title: CY62148E MoBL <sup>®</sup> , 4-Mbit (512 K × 8) Static RAM Document Number: 38-05442				
Revision	ECN	Orig. of Change	Submission Date	Description of Change
**	201580	AJU	01/08/04	New data sheet.
*A	249276	SYT	See ECN	Changed status from Advance Information to Preliminary. Updated Features (Added RTSOP II and removed FBGA Package). Updated Functional Description (Added RTSOP II and removed FBGA Package) UpdatedPin Configurations (Added RTSOP II and removed FBGA Package). Updated Operating Range (Updated Note 5 (Changed $V_{CC}$ stabilization time from $100~\mu s$ to $200~\mu s$ )). Updated Data Retention Characteristics (Changed maximum value of $I_{CCDR}$ parameter from $2.0~\mu A$ to $2.5~\mu A$ , changed minimum value of $t_{R}$ parameter from $100~\mu s$ to $t_{RC}$ ns). Updated Switching Characteristics (Changed minimum value of $t_{OHA}$ parameter from 6 ns to 10 ns for both 35 ns and 45 ns speed bin, changed maximum value of $t_{DCE}$ parameter from 15 ns to 18 ns for 35 ns speed bin, changed maximum value of $t_{HZOE}$ , $t_{HZWE}$ parameters from 12 ns to 15 ns for 35 ns speed bin and 15 ns to 18 ns for 35 ns speed bin and 40 ns to 35 ns for 45 ns speed bin changed maximum value of $t_{HZCE}$ parameter from 12 ns to 18 ns for 35 ns speed bin and 15 ns to 22 ns for 45 ns speed bin, changed minimum value of $t_{SCE}$ parameter from 15 ns to 18 ns for 35 ns speed bin, changed minimum value of $t_{SCE}$ parameter from 15 ns to 18 ns for 35 ns speed bin, changed minimum value of $t_{SCE}$ parameter from 15 ns to 18 ns for 35 ns speed bin and 20 ns to 22 ns for 45 ns speed bin). Updated Ordering Information (Corrected typo in Package Name column, also updated Ordering Codes (to include Pb-free packages)).
*B	414820	ZSD	See ECN	Changed status from Preliminary to Final Changed the address of Cypress Semiconductor Corporation on Page #1 from "3901 North First Street" to "198 Champion Court" Updated Features (Removed 35 ns speed bin). Updated Pin Configurations (Removed the Note "DNU pins have to be left floating or tied to $V_{SS}$ to ensure proper application." and its reference). Updated Product Portfolio (Removed 35 ns speed bin). Updated Maximum Ratings (Updated Note 3 to include current limit). Updated Electrical Characteristics (Removed "L" version of CY62148E, changed typical value of $I_{CC}$ parameter from 1.5 mA to 2 mA at $f=1$ MHz, changed maximum value of $I_{CC}$ parameter from 2 mA to 2.5 mA at $f=1$ MHz, changed typical value of $I_{CC}$ parameter from 12 mA to 15 mA at $f=f_{max}$ , removed $I_{SB1}$ parameter and its details, changed typical value of $I_{SB2}$ parameter from 0.7 $\mu$ A to 1 $\mu$ A and maximum value of $I_{SB2}$ parameter from 2.5 $\mu$ A to 7 $\mu$ A). Updated AC Test Loads and Waveforms (Changed the AC test load capacitance from 100 pF to 30 pF in Figure 2, changed test load parameters $R_1$ , $R_2$ , $R_{TH}$ and $V_{TH}$ from 1838 $\Omega$ , 994 $\Omega$ , 645 $\Omega$ and 1.75 $V$ to 1800 $\Omega$ , 990 $\Omega$ , 639 $\Omega$ and 1.77 $V$ ) Updated Data Retention Characteristics (Changed maximum value of $I_{CCDR}$ parameter from 2.5 $\mu$ A to 7 $\mu$ A, Added typical value for $I_{CCDR}$ parameter). Updated Switching Characteristics (Removed 35 ns speed bin, changed minimum value of $I_{LZCE}$ parameter from 3 ns to 5 ns, changed minimum value of $I_{LZCE}$ parameter from 22 ns to 18 ns, changed minimum value of $I_{DCDR}$ parameter from 30 ns to 35 ns, changed minimum value of $I_{DCDR}$ parameter from 30 ns to 35 ns, changed minimum value of $I_{DCDR}$ parameter from 30 ns to 35 ns, changed minimum value of $I_{DCDR}$ parameter from 30 ns to 35 ns, changed minimum value of $I_{DCDR}$ parameter from 30 ns to 35 ns, changed minimum value of $I_{DCDR}$ parameter from 30 ns to 35 ns, changed minimum value of $I_{DCDR}$ parameter from 30 ns to 35 ns,



# **Document History Page** (continued)

Revision	t Number: ECN	Orig. of Change	Submission Date	Description of Change	
*C	464503	NXR	See ECN	Updated Product Portfolio (Included Automotive Range). Updated Operating Range (Included Automotive Range). Updated Electrical Characteristics (Included Automotive Range). Updated Data Retention Characteristics (Included Automotive Range). Updated Switching Characteristics (Included Automotive Range). Updated Ordering Information (Updated ordering codes (Included Automotive parts and their related information)).	
*D	485639	VKN	See ECN	Updated Operating Range (Updated V <sub>CC</sub> to 4.5 V to 5.5 V).	
*E	833080	VKN	See ECN	Updated Electrical Characteristics (Added $V_{\rm IL}$ parameter for SOIC package, adde Note 9 and referred the same note in $V_{\rm IL}$ parameter for SOIC package).	
*F	890962	VKN	See ECN	Updated Pin Configurations (Added Note 1 related to SOIC package). Updated Product Portfolio (Included Automotive-A range and removed Automotive-E range). Updated Operating Range (Included Automotive-A range and removed Automotive-E range). Updated Electrical Characteristics (Included Automotive-A range and removed Automotive-E range, added Note 10 related to I <sub>SB2</sub> and referred the same note in I <sub>SB2</sub> parameter). Updated Data Retention Characteristics (Included Automotive-A range and removed Automotive-E range). Updated Switching Characteristics (Included Automotive-A range and removed Automotive-E range). Updated Ordering Information (Updated ordering codes (Added Automotive-A part and its related information).	
*G	2947039	VKN	06/10/2010	Updated Truth Table (Added Note 30 and referred the same note in CE column). Updated Ordering Information (Added "CY62148ELL-45ZSXA" part number). Updated Package Diagrams. Added Sales, Solutions, and Legal Information.	
*H	3006318	AJU	08/23/10	Updated Data Retention Characteristics (Added note 13 and referred the same note in I <sub>CCDR</sub> parameter). Added Ordering Code Definitions. Added Acronyms and Units of Measure. Updated in new template.	
*	3235744	RAME	04/20/2011	Updated Functional Description (Removed the line "For best practice recommendations, refer to the Cypress application note AN1064, SRAM System Guidelines"). Updated Package Diagrams.	
*J	3302815	RAME	07/14/2011	Updated in new template.	
*K	3539544	TAVA	03/01/2012	Updated Electrical Characteristics (Updated Note 9). Updated Package Diagrams.	
*L	3992135	MEMJ	05/06/2013	Updated Functional Description.  Updated Electrical Characteristics (Added one more Test Condition "V <sub>CC</sub> = 5.5 V, I <sub>OH</sub> = -0.1 mA" for V <sub>OH</sub> parameter and its corresponding values).  Updated Package Diagrams: spec 51-85081 – Changed revision from *D to *E.  Completing Sunset Review.	



# **Document History Page** (continued)

Document Title: CY62148E MoBL <sup>®</sup> , 4-Mbit (512 K × 8) Static RAM Document Number: 38-05442				
Revision	ECN	Orig. of Change	Submission Date	Description of Change
*M	4099045	VINI	08/19/2013	Updated Switching Characteristics: Added Note 15 and referred the same note in "Parameter" column.  Updated in new template.



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